

Electron-Assisted Hopping in Two Dimensions

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(February 1, 2008)

We have studied the non-ohmic effects in the conductivity of a two-dimensional system which undergoes the crossover from weak to strong localization with decreasing electron concentration. When the electrons are removed from equilibrium with phonons, the hopping conductivity depends only on the electron temperature. This indicates that the hopping transport in a system with a large localization length is assisted by electron-electron interactions rather than by the phonons.

72.15.Rn, 72.20.Ee, 72.20.Ht

Low-dimensional conductors demonstrate the crossover from weak localization (WL) to strong localization (SL) with decreasing electron concentration and/or increasing disorder. The WL regime, where electron motion is diffusive, and the localization and interaction effects reveal themselves as quantum corrections to the conductivity, is well-understood now (for an experimental review, see [1]). In the SL regime, electron transport is due to activated hopping between the localized states [2]. The mechanism of this hopping is still under debate. On one hand, it is common wisdom to treat this hopping as phonon-assisted (see, e.g., [2–4]). On the other hand, recent observations suggest that hopping is assisted by some other mechanism rather than phonons [5]. The idea of hopping due to electron-electron scattering in conductors with a large localization length has been also discussed in several theoretical papers (see, e.g. [6,7]).

In this Letter, we study the non-ohmic effects in the conductivity of a two-dimensional (2d) electron gas on both sides of the WL-SL crossover. It is shown that in either regime, diffusive or hopping, the nonlinear effects are well described by the model of "hot" electrons, and electron transport is controlled by the *electron* temperature rather than the phonon one. This indicates that hopping transport on the "insulating" side of the crossover is governed by the electron-electron interactions.

The resistance R of a two-dimensional (2d) *Si* δ -doped *GaAs* structure has been studied as a function of the magnetic field B and the bias current I in the temperature range $T = 0.05 - 1K$. A single δ -doped layer with concentration of *Si* donors $1.3 \times 10^{12} \text{ cm}^{-2}$ is $0.1 \mu\text{m}$ under the surface of the MBE-grown undoped *GaAs*. Two identical devices were formed by photolithography and wet etching on a chip with dimensions $5 \times 6 \times 0.5 \text{ mm}^3$; the area of each device between the voltage leads was $0.36 \times 0.12 \text{ mm}^2$. The electron concentration can be tuned by applying the voltage V_g to the gate electrode on top of each device. The measurements were done in the four-probe

configuration using a low-frequency ($f = 7Hz$) lock-in technique in the range $R < 10^6 \Omega$, and a dc current source and an electrometer for $10^6 \Omega < R < 10^9 \Omega$.

We have observed the WL-SL crossover with reducing the electron concentration (see the inset in Fig.3); the detailed analysis of the crossover will be given elsewhere [8]. The "zero-bias" dependences $R(T)$ are shown on both sides of the crossover in Figs.1 and 2. The logarithmic dependences $R(T)$, observed in the WL regime, are caused by the weak localization and interaction effects at $B = 0$, and by interaction only at $B = 0.1T$ (this field is sufficiently strong to suppress the T -dependence of the WL correction) [1]. Because of insufficient filtering of the external noise, $R(T)$ is saturated at $T \leq 0.15K$. This indicates that the electrons were never cooled below $0.1K$ in the WL regime. Electron transport becomes activated on the "insulating" side of the WL-SL crossover. The temperature dependence of the sheet resistance $R_\square$ is usually fitted in this regime as

$$R_\square(T) = R_{0\square}(T/1K)^m \exp(T_0/T)^\alpha, \quad (1)$$

several combinations of $m = 0 - 1$ and $\alpha = 1/3 - 1$ have been reported for different 2d systems [3–5,9,10]. A good fit for our data at $V_g = -0.7V$ is provided by Eq.(1) with $m = 0$ and $\alpha = 0.7$ (see Fig.2). Notice that in the SL regime, where the resistance at low T is by 10^5 larger than R in the WL regime, saturation of $R(T)$ is absent [11].

With increase of the bias current, the I - V curves become nonlinear in both WL and SL regimes. The insets in Figs. 1 and 2 show the resistance $R = V/I$ at a fixed mixing chamber (MC) temperature T versus the bias current power, $P = V \cdot I$. It is instructive to compare for both regimes the power that causes the decrease of R that is equivalent to increase of T by a fixed percentage (below we choose 10%). The procedure is illustrated by the insets of Figs.1 and 2. The resistance, measured at a fixed T and different I , has been compared with the zero-bias $R(1.1T)$. The corresponding values of P ,

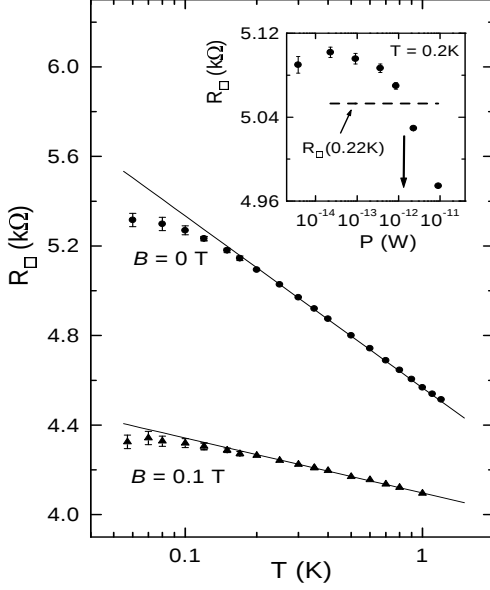


FIG. 1. The temperature dependences of the zero-bias $R_{\square}$ in the "metallic" regime ($V_g = 0.4V$, the electron concentration $n = 1 \times 10^{12} \text{ cm}^{-2}$) at $B = 0$ and $B = 0.1T$. The solid lines are the logarithmic fit $R_{\square}(T) = R_{\square}(1K) \left[1 - \alpha \frac{e^2 R_{\square}}{2\pi^2 \hbar} \ln(T/1K) \right]$ with $\alpha = 1.29$ ($B = 0$) and $\alpha = 0.52$ ($B = 0.1T$). The inset shows $R = V/I$ at a fixed MC temperature $T = 0.2K$ and $B = 0$ versus the power $P = V \cdot I$ released in the device. The horizontal dashed line corresponds to the zero-bias $R_{\square}$ at $T = 0.22K$.

shown by the vertical arrows in the insets, are plotted for $T = 0.05 - 1K$ in Fig.3. The same measurements have been repeated in the SL regime for several values of B . Within the experimental accuracy, no dependence $P(B)$ was observed in the range $B = 0 - 8T$ (the data for $B = 2T$ are shown in Fig.3). Below we analyze separately the data for the WL and SL regimes.

The WL regime. The low-temperature nonlinear effects in the WL regime have been intensively studied in recent years [12,13], they are accounted for by the electron overheating. The hot-electron model assumes that the non-equilibrium electron distribution function can be characterized by an effective electron temperature T_e , the electron-phonon interaction is the bottleneck in the energy transfer from the electrons to the heat sink, and the phonons are in equilibrium with the heat sink (the phonon temperature T_{ph} is the same as T). One can find T_e from comparison of $R(T)$ measured at different currents, provided the zero-bias R depends on T_e only.

All these assumptions can be justified in our experiment. Indeed, at sub-Kelvin temperatures, the electron-electron scattering rate is much greater than the electron-phonon one; this allows to introduce T_e . Both WL and

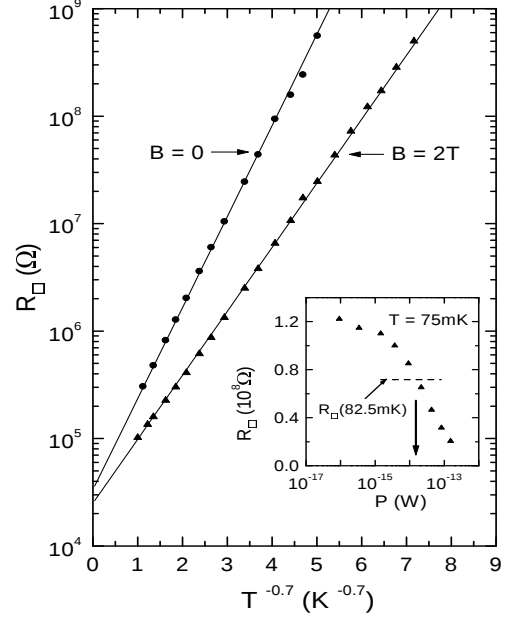


FIG. 2. The temperature dependences of the zero-bias $R_{\square}$ in the "insulating" regime ($V_g = -0.7V$) at $B = 0$ and $B = 2T$. The solid lines correspond to $R_{\square}(T) = 33.3k\Omega \cdot \exp[(2.6K/T)^{0.7}]$ at $B = 0$, and $R_{\square}(T) = 25k\Omega \cdot \exp[(1.57K/T)^{0.7}]$ at $B = 2T$. The inset shows $R = V/I$ at a fixed MC temperature $T = 75mK$ and $B = 0$ and $B = 2T$ versus the power $P = V \cdot I$ released in the device. The horizontal dashed line corresponds to the zero-bias $R_{\square}$ at $T = 82.5mK$.

interaction corrections are only T_e -dependent, since the dominant phase-breaking mechanism is the quasi-elastic electron-electron scattering [8,14,15]. We have also verified that the phonons in the GaAs chip remain in equilibrium with the mixing chamber (in other words that the resistance drop at large I is not due to heating of the whole chip relative to the thermometer monitoring the MC temperature). In this test, the zero-bias resistance of one of the devices (a phonon "thermometer") was measured at $T = 0.1K$ as a function of the Joule heat released in the other device on the same chip (a "heater") (see the inset of Fig.4). The power required for a 10%-increase of the temperature of the whole chip is by 3.5 orders of magnitude greater than the power that causes nonlinear effects in the experiments when the same device combines the functions of the "heater" and the "thermometer".

Since the outdiffusion of "hot" electrons in cooler leads can be neglected for our samples at $T > 0.1K$ [16,13], the energy is transferred from electrons to the heat sink due to the electron-phonon interaction only. At $T \leq 1K$, the device enters the hydrodynamic regime $q_t l < 1$ [$q_t = k_B T / \hbar u_t$ is the wave vector of a transverse phonon, u_t is the transverse sound velocity ($\simeq 3 \cdot 10^3 m/s$ for GaAs),

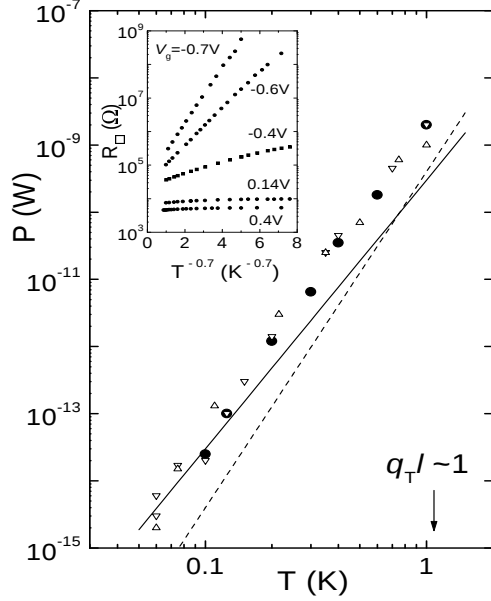


FIG. 3. The temperature dependence of the power $P = V \cdot I$, which causes the increase of the electron temperature T_e by 10% over the MC temperature T : $\bullet$ - in the WL regime ($V_g = 0.4V$, $B = 0$); ∇ and $\triangle$ in the SL regime ($V_g = -0.7V$) at $B = 0$ and $B = 2T$, correspondingly. The dependences $P(T_e = 1.1T)$ are calculated for the electron cooling due to the piezoelectric coupling: the solid line - for the disordered case (Eq. 2), the dashed line - for the clean case (Eq. 3). The inset: the zero-bias dependences $R_\square(T)$ for several values of V_g .

the electron mean free path $l \sim 20nm$ at $V_g = 0.4V$]. The low- T data are in agreement with calculations of the energy flow from the 2d electrons in GaAs to the bulk phonons due to the piezoelectric coupling at $q_t l < 1$ [17]:

$$P[W] \simeq 7 \cdot 10^{-2} \cdot \frac{e^2 R_\square}{h} \cdot A \cdot (T_e^4 - T^4) [K^4] \quad (2)$$

where $R_\square$ is the sheet resistance, and A is the area of the device (the solid line in Fig.3). At $T \sim 1K$, the experimental values of P exceed by a factor of 4–5 both (2) and the result for the clean case $q_t l > 1$ [18]:

$$P[W] \simeq 1.7 \cdot 10^6 \cdot n^{-1/2} \cdot A \cdot (T_e^5 - T^5) [K^5] \quad (3)$$

(the dashed line in Fig.3). Our experimental dependence $P(T)$ is consistent with the data for the GaAs heterostructures with larger $l \sim 0.3 - 1\mu m$, obtained in Ref. [13] at $T = 0.1 - 0.4K$.

The SL regime. The striking similarity of the dependences $P(T)$ obtained in the "metallic" and "insulating" regimes indicate that the mechanism of nonlinearity is also the same on both sides of the WL-SL crossover. Figure 4 shows that the hot-electron model describes very

well the dependences $R(P)$ in the SL regime [19]. It might be, of course, just a coincidence: some field effects in the SL regime could produce, in principle, similar nonlinearities. However, measurements in the magnetic field rule out this possibility. Indeed, all the models of non-ohmic hopping transport predict the dependence of the characteristic electric field E on the localization length ξ [20]. In the magnetic field, which breaks the time-reversal symmetry within the localization domain, ξ increases significantly [21]: the exponentially strong negative magnetoresistance, which has been observed for 1d and 2d δ -doped GaAs structures (see Fig. 2), is a signature of this B -induced growth of ξ [22,14,8]. Despite of the increase of ξ in strong magnetic fields, no dependence $P(B)$ was observed [23].

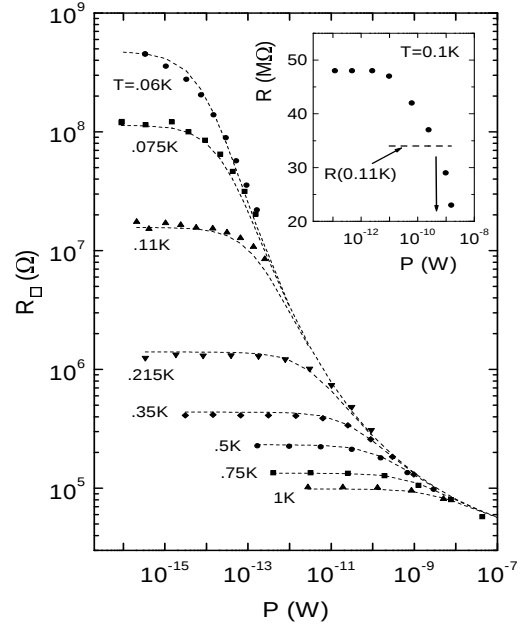


FIG. 4. The resistance $R = V/I$ in the SL regime ($V_g = -0.7V$, $B = 2T$) at different MC temperatures as a function of the power $P = V \cdot I$ released in the device. The dashed lines are the fit $R_\square(T) = R_\square \exp[(T_0/T_e)^{0.7}]$ with $R_\square = 25k\Omega$, $T_0 = 1.57K$ (see Fig.2) and T_e found from $P = 3.7 \cdot 10^{-9} [W] (T_e^{4.5} - T^{4.5})$, the best approximation for the experimental data in Fig.3. The inset: the zero-bias R in the SL regime ($V_g = -0.6V$, $T = 0.1K$) versus the power released in the other device on the same chip. The horizontal dashed line corresponds to the zero-bias R at $T = 0.11K$.

The applicability of the hot-electron model to the SL regime indicates that: a) the electron-phonon interaction remains the same on the "insulating" side of the crossover, and b) the resistance in the SL regime depends on the electron temperature only. The former conclusion is not very surprising. Indeed, the localization length, which can be estimated from the mag-

netoresistance [22,14,8], is large close to the crossover ($\xi \sim 0.15\mu m$ for $V_g = -0.7V$). The electron motion is still diffusive at distances $\leq \xi$, with the l values similar to that in the WL regime. Since $q_T\xi \sim 1$ even at $T = 50mK$, one should not expect strong modification of the electron-phonon interaction on the "insulating" side of the crossover. The latter conclusion, however, implies that the hopping transport is not phonon-assisted, instead, it is caused by electron-electron interactions.

Recently, the authors of Ref. [5] came to a similar conclusion that hopping in *GaAs/AlGaAs* heterostructures is not phonon-assisted. This conclusion was based on analysis of the prefactor $R_{0\Box}$ in Eq. (1). Indeed, $R_{0\Box}$ is expected to depend on temperature and material properties for the phonon-assisted hopping. Instead, the experimental $R_{0\Box}$ values are material-independent. They are usually close to the quantum resistance $R_Q = h/e^2$ [4,5,9,10]; this value is by several orders of magnitude smaller than the estimate for the phonon-assisted transport. In our experiment, $R_{0\Box}$ is also close to R_Q for both $B = 0$ and strong magnetic fields (see Fig. 2).

Previously, the hot-electron model has been applied to the non-ohmic effects in hopping conductivity of *three-dimensional* heavily-doped *Ge* [23]. Our 2d structures have two important features that help to attribute unambiguously the observed nonlinear effects to the electron overheating: a) observation of the WL-SL crossover allows direct comparison with the well-understood "metallic" regime, and b) for the 2d electron gas embedded in bulk *GaAs*, it is much easier to maintain equilibrium between the phonons and the heat sink than in the case of the 3d uniformly-doped samples.

To summarize, we have shown that the non-ohmic effects in the conductivity of 2d Si δ -doped *GaAs* structures, observed on both sides of the WL-SL crossover, are caused by the electron overheating. The heat flow from the hot 2d electrons to equilibrium 3d phonons in the WL and SL regimes is well described by recent calculations for the piezoelectric coupling in the hydrodynamic regime [17]. The conductivity in the hopping regime depends on the electron temperature rather than the phonon one, similar to the WL regime. This observation provides strong evidence that electron hopping in disordered systems with a large localization length is assisted by the electron-electron interactions.

We thank E. Abrahams, B. Altshuler, I. Aleiner, B. Shklovskii, M. Raikh, M. Reizer, and B. Spivak for helpful discussions. This work was partially supported by ARO-administered MURI grant DAAD 19-99-1-0252 and by the Rutgers Office of the Research and Sponsored Programs. D. R. gratefully acknowledges financial support of the DFG Graduiertenkolleg 384.

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